Applicant(s)/Patent Under Reexamination 10/721,751 SHIINA ET AL. Notice of References Cited Art Unit Examiner Page 1 of 1 3611 Lee Lum

Application/Control No.

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,491,131	12-2002	Appleyard, Michael	180/444
	В	US-6,776,064	08-2004	Bucholz et al.	74/425
	С	US-4,475,413	10-1984	Higuchi, Megumu	74/422
	D	US-6,041,887	'03-2000	Kojo et al.	180/446
	E	US-6,725,964	04-2004	Appleyard, Michael	180/444
	F	US-6,357,313	03-2002	Appleyard, Michael	74/388PS
	G	US-4,444,070	04-1984	Yanai, Tokiyoshi	74/422
	н	US-4,228,696	10-1980	Jablonsky, Erich	74/499
	1	US-4,011,764	03-1977	Buck et al.	74/499
	J	US-6,470,994	10-2002	Shimizu et al.	180/446
	к	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Ν					
	0					
	Р					
	Q					
	R					
	s					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	·
	V	
	w	
	х	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.